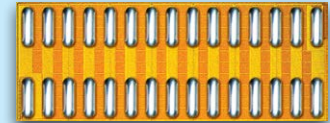


## EPC2022 – Enhancement Mode Power Transistor

 $V_{DS}$ , 100 V $R_{DS(on)}$ , 3.2 m $\Omega$  $I_D$ , 90 A

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low  $R_{DS(on)}$ , while its lateral device structure and majority carrier diode provide exceptionally low  $Q_G$  and zero  $Q_{RR}$ . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.



Die Size: 6.05 x 2.3 mm

**EPC2022** eGaN® FETs are supplied only in passivated die form with solder bumps.

- High Speed DC-DC Conversion
- Motor Drive
- Industrial Automation
- Synchronous Rectification
- Inrush Protection
- Class-D Audio

Maximum Ratings			
PARAMETER		VALUE	UNIT
$V_{DS}$	Drain-to-Source Voltage (Continuous)	100	V
	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	120	
$I_D$	Continuous ( $T_A = 25^\circ\text{C}$ , $R_{\theta JA} = 2.5^\circ\text{C/W}$ )	90	A
	Pulsed (25°C, $T_{PULSE} = 300 \mu\text{s}$ )	390	
$V_{GS}$	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
$T_J$	Operating Temperature	-40 to 150	°C
$T_{STG}$	Storage Temperature	-40 to 150	

Thermal Characteristics			
PARAMETER		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.4	°C/W
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board	1.1	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	42	

Note 1:  $R_{\theta JA}$  is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See [https://epc-co.com/epc/documents/product-training/Appnote\\_Thermal\\_Performance\\_of\\_eGaN\\_FETs.pdf](https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf) for details.

Static Characteristics ( $T_J = 25^\circ\text{C}$ unless otherwise stated)						
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$BV_{DSS}$	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V}$ , $I_D = 0.9 \text{ mA}$	100			V
$I_{DSS}$	Drain-Source Leakage	$V_{DS} = 80 \text{ V}$ , $V_{GS} = 0 \text{ V}$		0.1	0.7	mA
$I_{GSS}$	Gate-to-Source Forward Leakage	$V_{GS} = 5 \text{ V}$		1	9	
	Gate-to-Source Reverse Leakage	$V_{GS} = -4 \text{ V}$		0.1	0.7	
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 13 \text{ mA}$	0.8	1.4	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}$ , $I_D = 25 \text{ A}$		2.4	3.2	m $\Omega$
$V_{SD}$	Source-Drain Forward Voltage	$I_S = 0.5 \text{ A}$ , $V_{GS} = 0 \text{ V}$		1.8		V

All measurements were done with substrate connected to source.

Dynamic Characteristics <sup>#</sup> (T <sub>j</sub> = 25°C unless otherwise stated)						
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
C <sub>ISS</sub>	Input Capacitance	V <sub>DS</sub> = 50 V, V <sub>GS</sub> = 0 V		1400	1690	pF
C <sub>OSS</sub>	Output Capacitance			840	1260	
C <sub>RSS</sub>	Reverse Transfer Capacitance			7		
C <sub>OSS(ER)</sub>	Effective Output Capacitance, Energy Related (Note 2)	V <sub>DS</sub> = 0 to 50 V, V <sub>GS</sub> = 0 V		1090		
C <sub>OSS(TR)</sub>	Effective Output Capacitance, Time Related (Note 3)			1410		
R <sub>G</sub>	Gate Resistance			0.3		Ω
Q <sub>G</sub>	Total Gate Charge	V <sub>DS</sub> = 50 V, V <sub>GS</sub> = 5 V, I <sub>D</sub> = 25 A		13	16	nC
Q <sub>GS</sub>	Gate-to-Source Charge	V <sub>DS</sub> = 50 V, I <sub>D</sub> = 25 A		3.4		
Q <sub>GD</sub>	Gate-to-Drain Charge			2.4		
Q <sub>G(TH)</sub>	Gate Charge at Threshold			2.1		
Q <sub>OSS</sub>	Output Charge	V <sub>DS</sub> = 50 V, V <sub>GS</sub> = 0 V		71	107	
Q <sub>RR</sub>	Source-Drain Recovery Charge			0		

All measurements were done with substrate connected to source.

# Defined by design. Not subject to production test.

Note 2: C<sub>OSS(ER)</sub> is a fixed capacitance that gives the same stored energy as C<sub>OSS</sub> while V<sub>DS</sub> is rising from 0 to 50% BV<sub>DSS</sub>.

Note 3: C<sub>OSS(TR)</sub> is a fixed capacitance that gives the same charging time as C<sub>OSS</sub> while V<sub>DS</sub> is rising from 0 to 50% BV<sub>DSS</sub>.

Figure 1: Typical Output Characteristics at 25°C

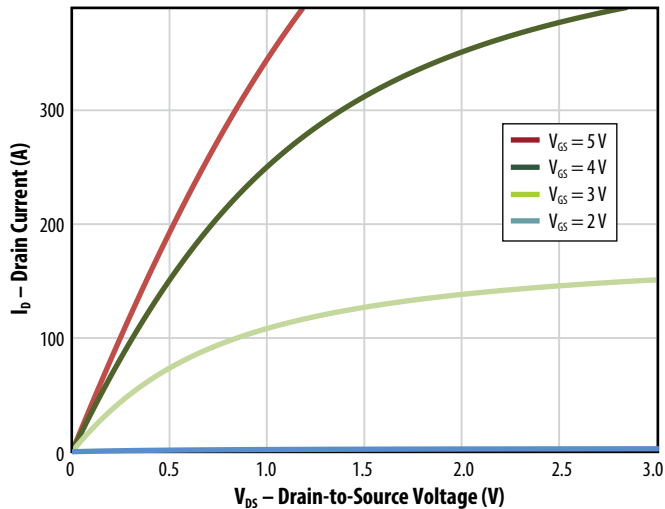


Figure 2: Typical Transfer Characteristics

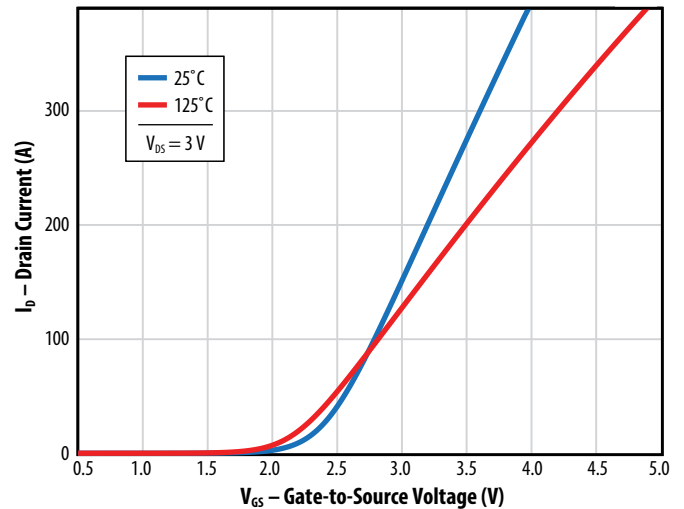


Figure 3: R<sub>DS(on)</sub> vs. V<sub>GS</sub> for Various Drain Currents

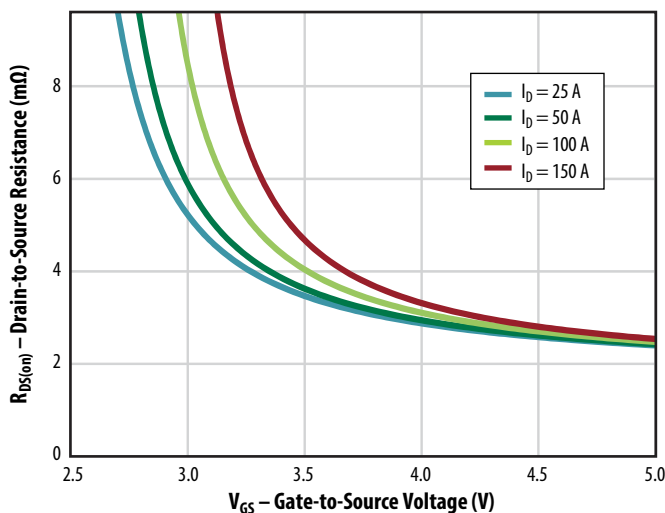


Figure 4: R<sub>DS(on)</sub> vs. V<sub>GS</sub> for Various Temperatures

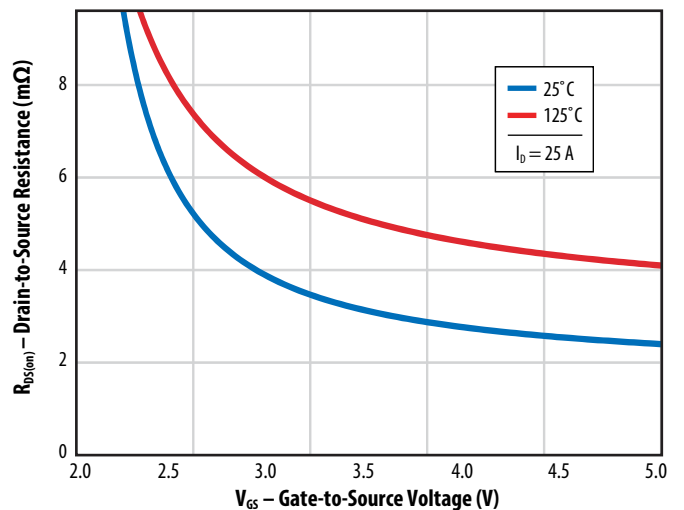


Figure 5a: Typical Capacitance (Linear Scale)

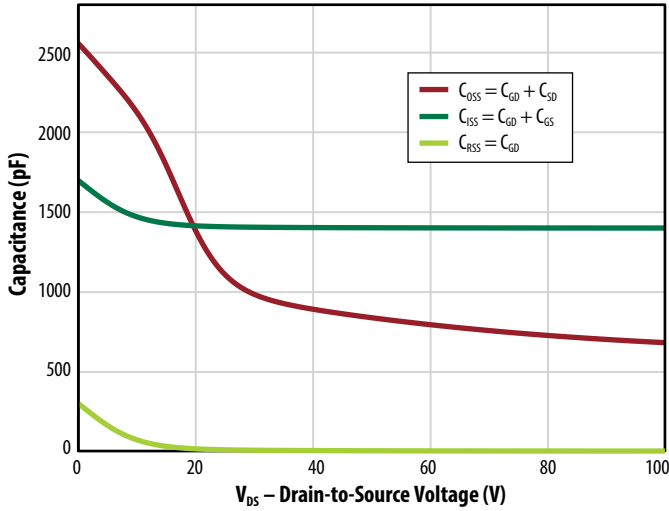


Figure 5b: Typical Capacitance (Log Scale)

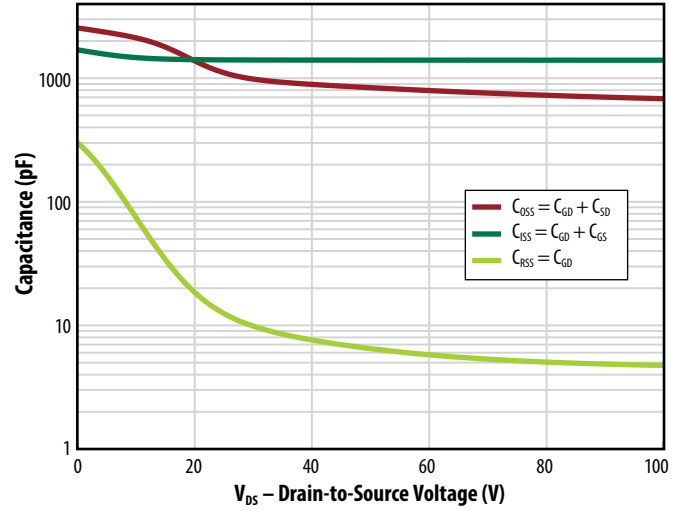


Figure 6: Typical Gate Charge

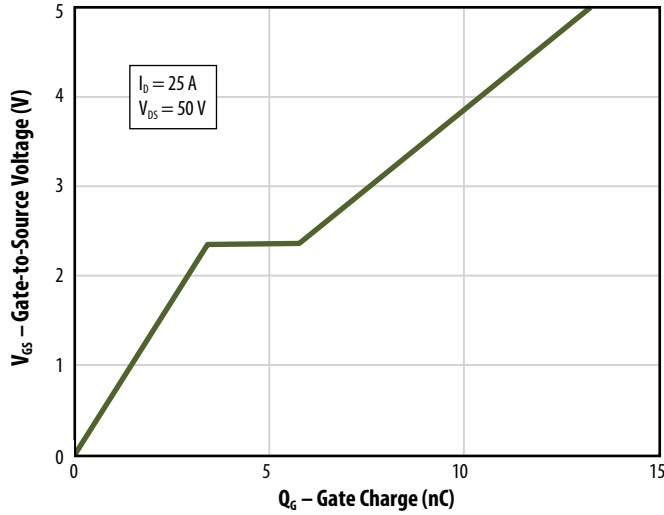


Figure 7: Typical Reverse Drain-Source Characteristics

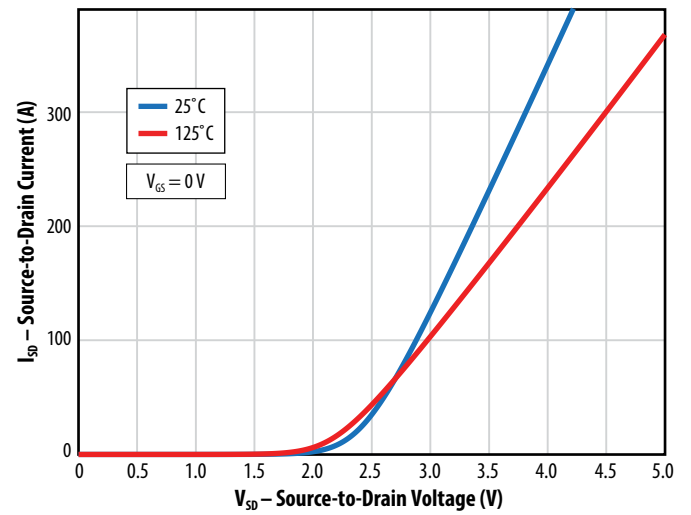


Figure 8: Normalized On-State Resistance vs. Temperature

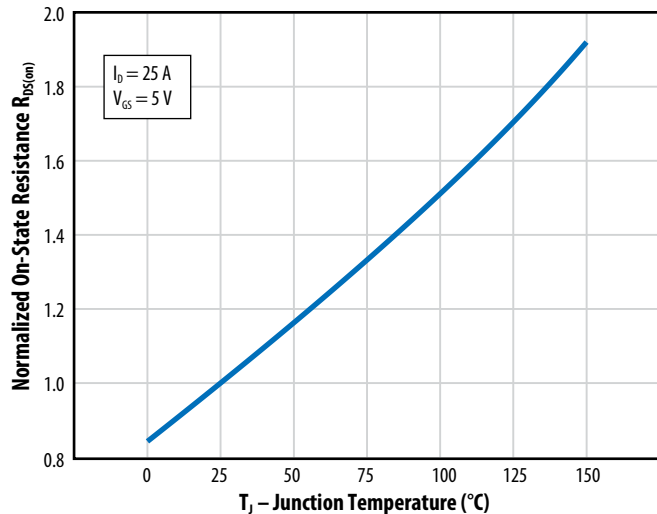
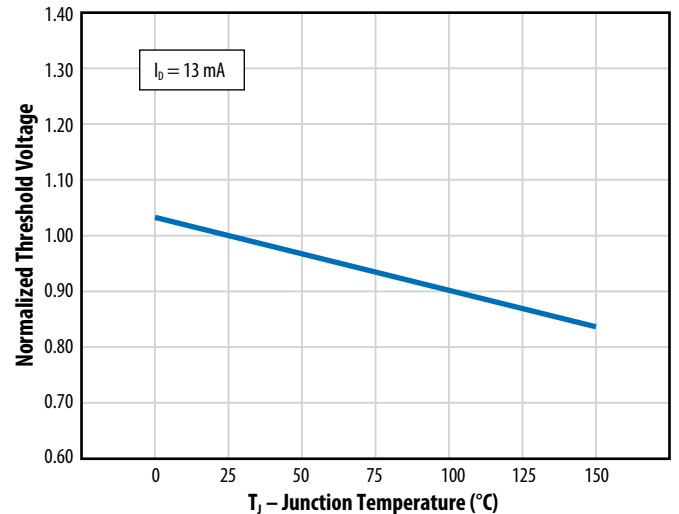


Figure 9: Normalized Threshold Voltage vs. Temperature



Note: Negative gate drive voltage increases the reverse drain-source voltage.  
EPC recommends 0 V for OFF.

Figure 10: Gate Leakage Current

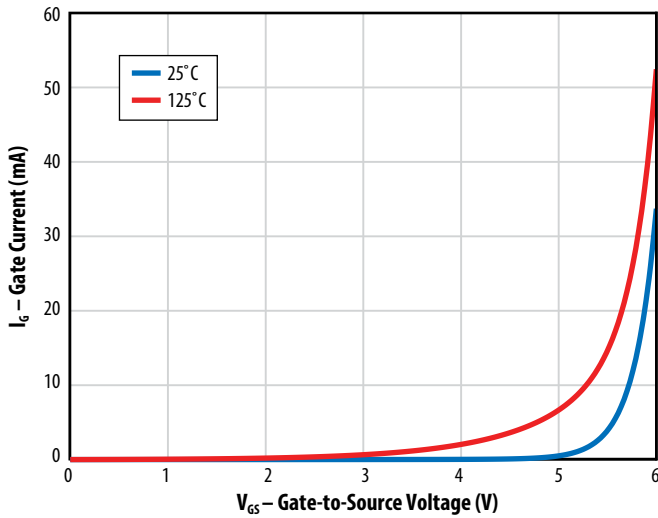


Figure 11: Safe Operating Area

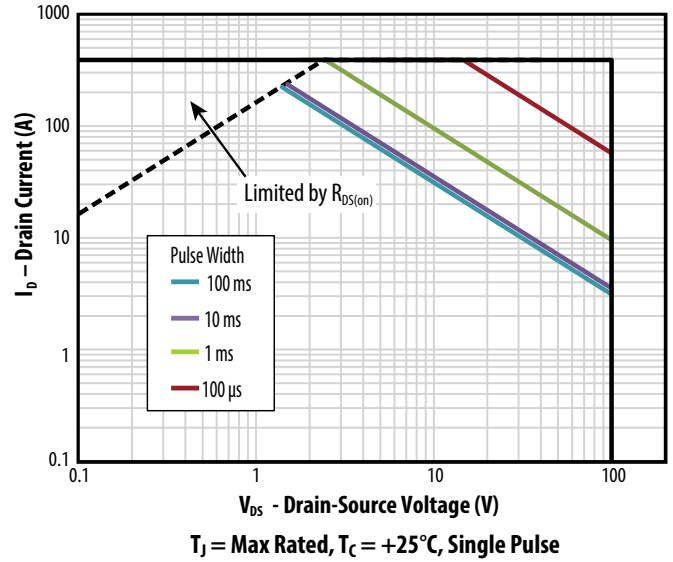
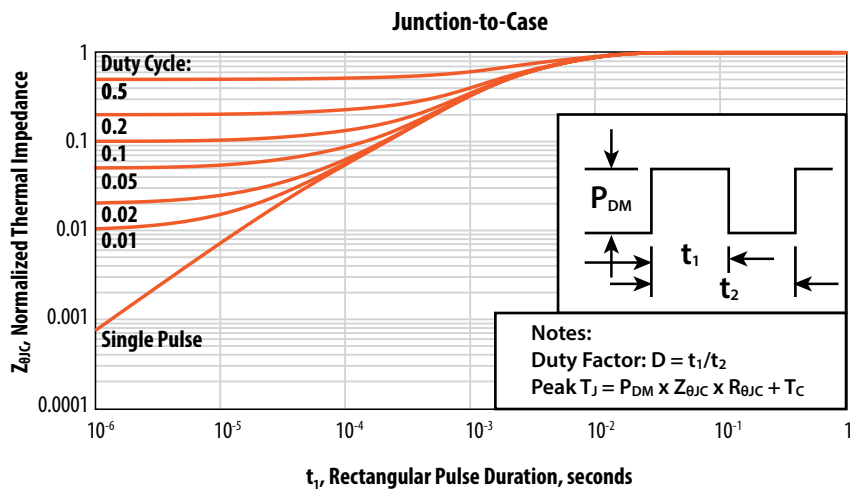
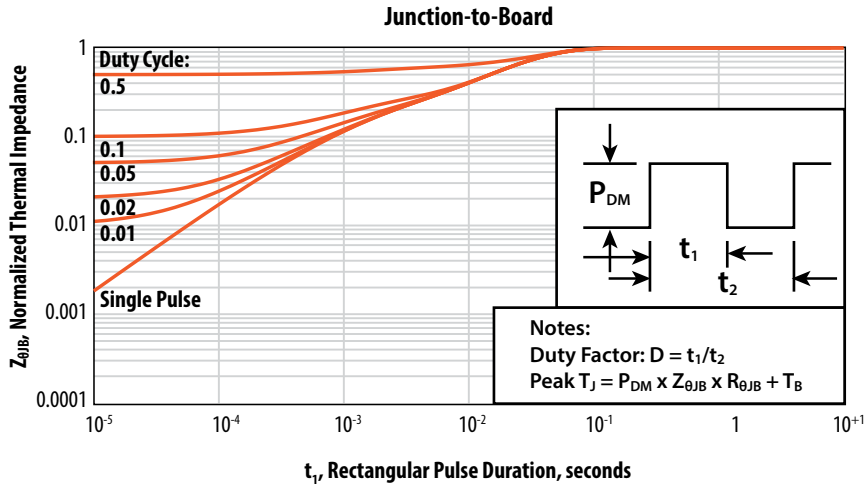
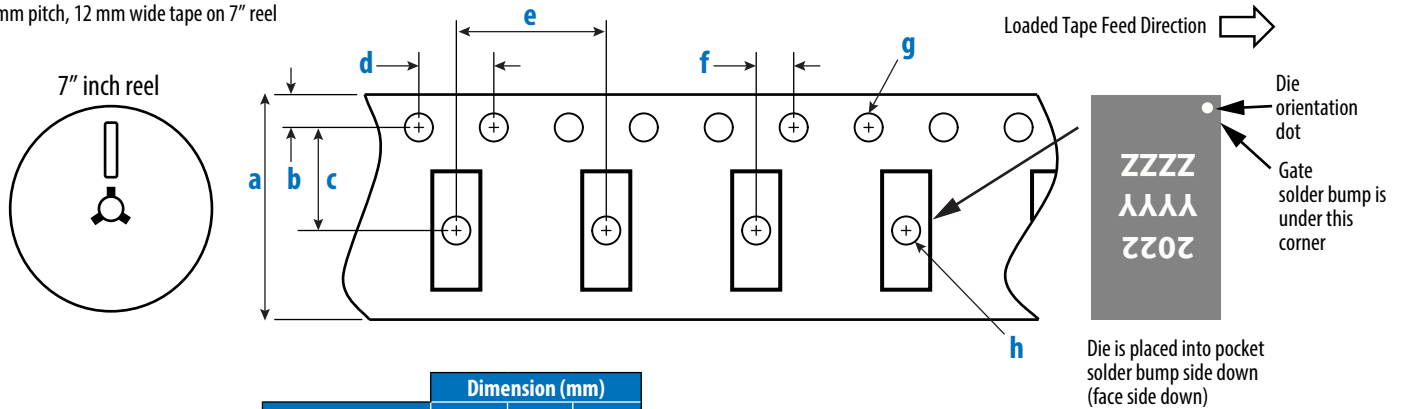


Figure 12: Transient Thermal Response Curves



**TAPE AND REEL CONFIGURATION**

8 mm pitch, 12 mm wide tape on 7" reel



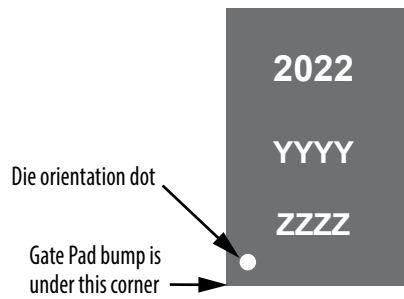
EPC2022 (Note 1)	Dimension (mm)		
	Target	MIN	MAX
a	12.00	11.90	12.30
b	1.75	1.65	1.85
c (Note 2)	5.50	5.45	5.55
d	4.00	3.90	4.10
e	8.00	7.90	8.10
f (Note 2)	2.00	1.95	2.05
g	1.50	1.50	1.60
h	1.50	1.50	1.75

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/ JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

Die is placed into pocket solder bump side down (face side down)

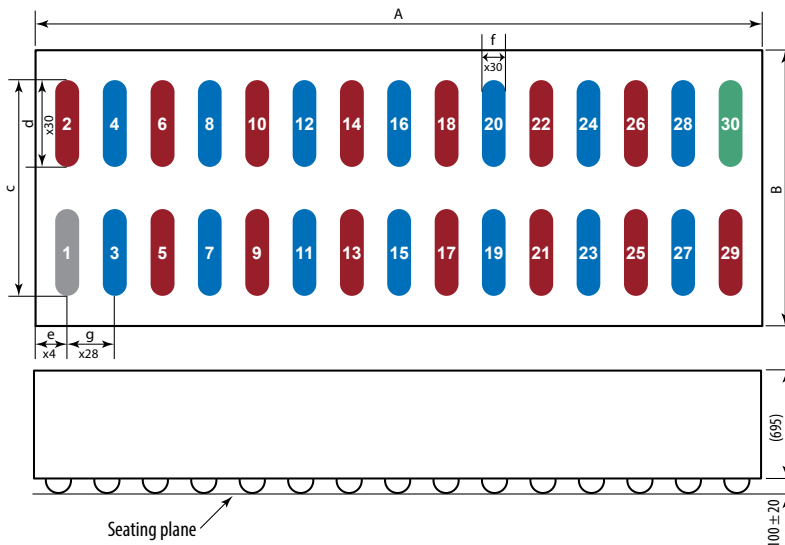
**DIE MARKINGS**



Part Number	Laser Markings		
	Part # Marking Line 1	Lot Date Code Marking Line 2	Lot Date Code Marking Line 3
EPC2022	2022	YYYY	ZZZZ

**DIE OUTLINE**

Solder Bump View

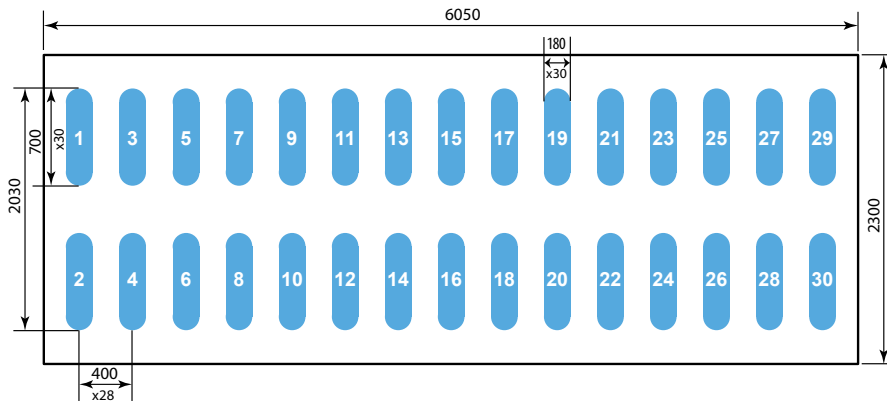


DIM	Micrometers		
	MIN	Nominal	MAX
A	6020	6050	6080
B	2270	2300	2330
c	2047	2050	2053
d	717	720	723
e	210	225	240
f	195	200	205
g	400	400	400

Pad 1 is Gate;  
 Pads 2, 5, 6, 9, 10, 13, 14, 17, 18, 21, 22, 25, 26, 29 are Source;  
 Pads 3, 4, 7, 8, 11, 12, 15, 16, 19, 20, 23, 24, 27, 28 are Drain;  
 Pad 30 is Substrate.\*

\*Substrate pin should be connected to Source

**RECOMMENDED LAND PATTERN**  
(units in  $\mu\text{m}$ )

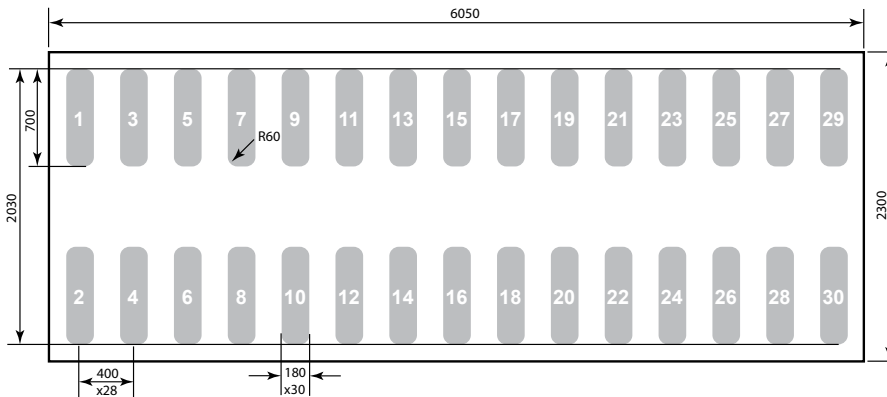


Land pattern is solder mask defined.

- Pad 1 is Gate;
- Pads 2, 5, 6, 9, 10, 13, 14, 17, 18, 21, 22, 25, 26, 29 are Source;
- Pads 3, 4, 7, 8, 11, 12, 15, 16, 19, 20, 23, 24, 27, 28 are Drain;
- Pad 30 is Substrate.\*

\*Substrate pin should be connected to Source

**RECOMMENDED STENCIL DRAWING**  
(units in  $\mu\text{m}$ )



Recommended stencil should be 4 mil (100  $\mu\text{m}$ ) thick, must be laser cut, openings per drawing.

Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

Additional assembly resources available at <https://epc-co.com/epc/design-support/assemblybasics>

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EPC Patent Listing: <https://epc-co.com/epc/about-epc/patents>

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Revised June 2023